



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Confirmation No. 4508

Toshifumi KIMBA et al.

Docket No 2000-1706A

Serial No. 09/734,737

Group Art Unit 2877

Filed December 13, 2000

Examiner Hoa Q. Pham

SUBSTRATE FILM THICKNESS  
MEASUREMENT METHOD, SUBSTRATE  
FILM THICKNESS MEASUREMENT  
APPARATUS AND SUBSTRATE  
PROCESSING APPARATUS

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**RESPONSE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Restriction Requirement of August 8, 2003, Applicant hereby elects Species C without traverse for further prosecution. It is submitted that claims 29-33, 48-52 and 70-75 read on the elected species.

In view of the above election and amendments, a full examination on the merits of this application is respectfully requested.

Respectfully submitted,

Toshifumi KIMBA et al.

By: 

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August 29, 2003

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